

ABSTRACT OF THE DISCLOSURE

5 A method of testing error correction/detection logic may involve providing each
of a set of n data bit combinations to the error correction/detection logic. Each data bit
combination has n bits, and the n data bit combinations may be created by creating an
initial data bit combination whose data bits have the same logical value and then shifting
a bit having the opposite value across the initial data bit combination. In response to
being provided with the n data bit combinations, the error correction/detection logic
generates a set of check bits for each of the n data bit combinations. The set of check bits
10 generated by the error correction/detection logic for each of the n data bit combinations
may then be verified.

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